

## Ultra Low Power Consumption

- 150  $\mu$ A/MHz in active mode (24.5 MHz clock)
- 2  $\mu$ s wakeup time
- 10 nA sleep mode with memory retention
- 50 nA sleep mode with brownout detector
- 300 nA sleep mode with LFO
- 600 nA sleep mode with external crystal

## Supply Voltage 1.8 to 3.6 V

- Built-in LDO regulator allows a high analog supply voltage and low digital core voltage
- 2 built-in supply monitors (brownout detector) for sleep mode and active modes

## 12-Bit or 10-Bit Analog to Digital Converter

- $\pm 1$  LSB INL (10-bit mode);  $\pm 1.5$  LSB INL (12-bit mode) no missing codes
- Programmable throughput up to 300 ksp/s (10-bit mode) or 75 ksp/s (12-bit mode)
- 10 external inputs
- On-chip voltage reference; 0.5x gain allows measuring voltages up to twice the reference voltage
- 16-bit auto-averaging accumulator with burst mode provides increased ADC resolution
- Data dependent windowed interrupt generator
- Built-in temperature sensor

## Capacitive Sense Interface

- Supports buttons, sliders, wheels, and capacitive proximity sensing
- Fast 40  $\mu$ s per channel conversion time
- 16-bit resolution, 14 input channels
- Auto scan and wake-on-touch
- Auto-accumulate up to 64x samples

## Analog Comparator

- Programmable hysteresis and response time
- Configurable as wake-up or reset source

## 6-Bit Programmable Current Reference

- Up to  $\pm 500$   $\mu$ A, can be used as a bias or for generating a custom reference voltage
- PWM enhanced resolution mode

## High-Speed 8051 $\mu$ C Core

- Pipelined instruction architecture; executes 70% of instructions in 1 or 2 system clocks
- Up to **25 MIPS** throughput with 25 MHz clock
- Expanded interrupt handler

## Memory

- 512 bytes RAM
- 8 kB Flash; in-system programmable

## Digital Peripherals

- 17 port I/O; high sink current and programmable drive strength
- Hardware SMBus<sup>TM</sup>/I<sup>2</sup>C<sup>TM</sup>, SPI<sup>TM</sup>, and UART serial ports available concurrently
- Four general purpose 16-bit counter/timers
- Programmable 16-bit counter/timer array with three capture/compare modules and watchdog timer

## Clock Sources

- Internal oscillators: 24.5 MHz, 2% accuracy supports UART operation; 20 MHz low power oscillator requires very little bias current.
- External oscillator: Crystal, RC, C, or CMOS Clock
- SmartClock oscillator: 32 kHz Crystal or internal
- Can switch between clock sources on-the-fly; useful in implementing various power saving modes

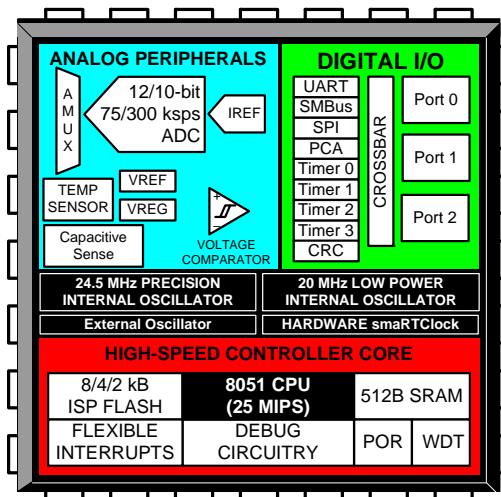
## On-Chip Debug

- On-chip debug circuitry facilitates full-speed, non-intrusive in-system debug (no emulator required)
- Provides breakpoints, single stepping
- Inspect/modify memory and registers
- Complete development kit

## Temperature Range: -40 to +85 $^{\circ}$ C

## Full Technical Data Sheet

- C8051F99x-C8051F98x



# C8051F996-GDI

## 1. Ordering Information

Table 1.1. Product Selection Guide

Ordering Part Number	MIPS (Peak)	Flash Memory (kB)	RAM (Bytes)	SmaRTClock Real Time Clock	SMBus/I <sup>2</sup> C, UART, Enhanced SPI	Timers (16-bit)	Programmable Counter Array	Digital Port I/Os	Analog-to-Digital Converter Inputs	ADC with Internal Voltage Reference and Temperature Sensor	Capacitive Touch (QuickSense™) Inputs	Programmable Current Reference	Analog Comparators	Package
C8051F996-GDI	25	8	512	✓	✓	4	✓	17	10	12-bit	14	✓	1	Tested Die in Wafer Form

## 2. Pin Definitions

Table 2.1 lists the pin definitions for the C8051F996-GDI. For a full description of each pin, refer to the C8051F99x-C8051F98x data sheet.

**Table 2.1. Pin Definitions for the C8051F996-GDI**

Name	Physical Pad Number	Type	Description
V <sub>DD</sub>	3	P In	Power Supply Voltage. Must be 1.8 to 3.6 V.
GND	2	G	Required Ground.
RST/	6	D I/O	Device Reset. Open-drain output of internal POR or V <sub>DD</sub> monitor. An external source can initiate a system reset by driving this pin low for at least 15 $\mu$ s. A 1 k $\Omega$ to 5 k $\Omega$ pullup to V <sub>DD</sub> is recommended.
C2CK		D I/O	Clock signal for the C2 Debug Interface.
P2.7/	7	D I/O	Port 2.7. This pin can only be used as GPIO. The Crossbar cannot route signals to this pin and it cannot be configured as an analog input.
C2D		D I/O	Bi-directional data signal for the C2 Debug Interface.
P1.6/	9	D I/O	Port 1.6.
XTAL3		A In	SmaRTClock Oscillator Crystal Input.
P1.7/	8	D I/O	Port 1.7.
XTAL4		A Out	SmaRTClock Oscillator Crystal Output.
P0.0/	1	D I/O or A In	Port 0.0.
V <sub>REF</sub>		A In	External V <sub>REF</sub> Input.
P0.1/	25	D I/O or A In	Port 0.1.
AGND		G	Optional Analog Ground.

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**Table 2.1. Pin Definitions for the C8051F996-GDI (Continued)**

Name	Physical Pad Number	Type	Description
P0.2/  XTAL1/  RTCOUT	24	D I/O or A In  A In  D Out	Port 0.2.  External Clock Input. This pin is the external oscillator return for a crystal or resonator.  Buffered SmaRTClock oscillator output.
P0.3/  XTAL2/   WAKEOUT	23	D I/O or A In  A Out  D In  A In  D Out	Port 0.3.  External Clock Output. This pin is the excitation driver for an external crystal or resonator.  External Clock Input. This pin is the external clock input in external CMOS clock mode.  External Clock Input. This pin is the external clock input in capacitor or RC oscillator configurations.  Wake-up request signal to wake up external devices.
P0.4/  TX	22	D I/O or A In  D Out	Port 0.4.  UART TX Pin.
P0.5/  RX	21	D I/O or A In  D In	Port 0.5.  UART RX Pin.
P0.6/  CNVSTR	20	D I/O or A In  D In	Port 0.6.  External Convert Start Input for ADC0.
P0.7/  IREF0	19	D I/O or A In  A Out	Port 0.7.  IREF0 Output.
P1.0  CP0+	16	D I/O or A In  A In	Port 1.0. May also be used as SCK for SPI1.  Comparator0 positive input.

**Table 2.1. Pin Definitions for the C8051F996-GDI (Continued)**

Name	Physical Pad Number	Type	Description
P1.1	14	D I/O or A In	Port 1.1.
CP0-		A In	Comparator0 negative input.
P1.2	13	D I/O or A In	Port 1.2.
P1.3	12	D I/O or A In	Port 1.3.
P1.4	11	D I/O or A In	Port 1.4.
P1.5	10	D I/O or A In	Port 1.5.

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## 3. Bonding Instructions

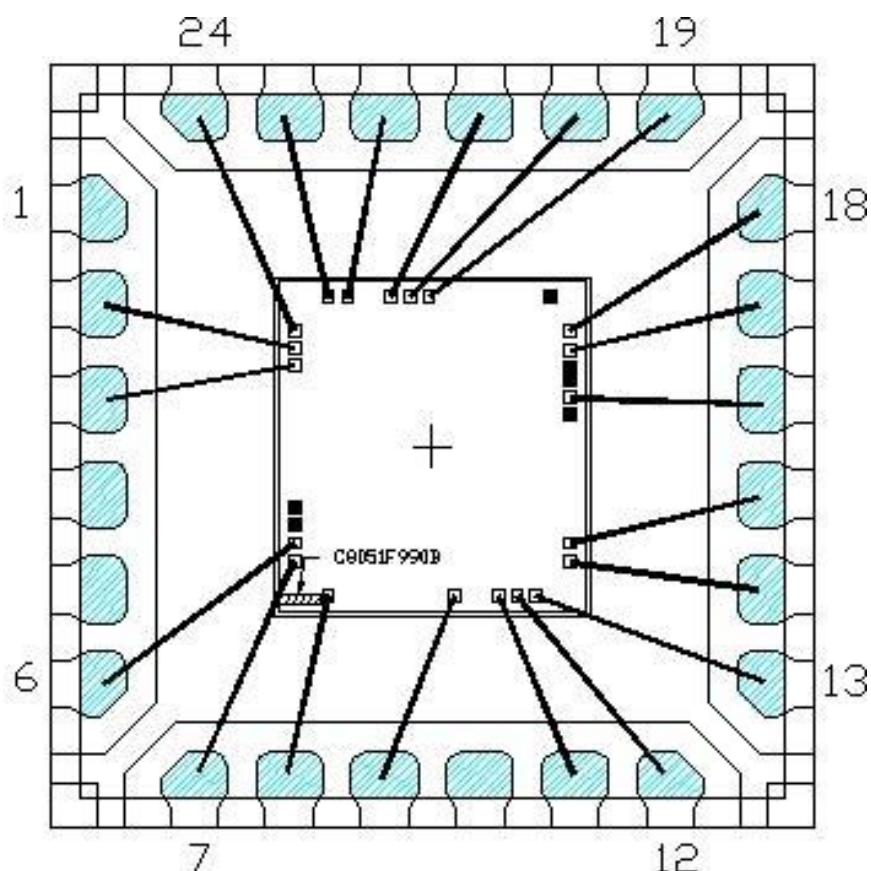


Figure 3.1. Die Bonding (QFN-24)

Table 3.1. Bond Pad Coordinates (Relative to Center of Die)

Physical Pad Number	Example Package Pin Number (QFN-24)	Package Pin Name	Physical Pad X (μm)	Physical Pad Y (μm)
1	24	P0.0/VREF	-724	606
	1	NC		
2	2	GND	-724	515
3	3	VDD	-724	429
4	Reserved	—	-724	-322
5	Reserved	—	-724	-413
6	6	/RST/C2CK	-724	-506
7	7	P2.7/C2D	-724	-606

**\*Note:** Pins marked “Reserved” should not be connected.

**Table 3.1. Bond Pad Coordinates (Relative to Center of Die) (Continued)**

Physical Pad Number	Example Package Pin Number (QFN-24)	Package Pin Name	Physical Pad X (μm)	Physical Pad Y (μm)
8	8	P1.7/XTAL4	–545	–785
9	9	P1.6/XTAL3	117	–785
	10	NC		
10	11	P1.5	345	–785
11	12	P1.4	445	–785
12	13	P1.3	545	–785
13	14	P1.2	724	–606
14	15	P1.1/CP0–	724	–506
15	Reserved	—	724	168
16	16	P1.0/CP0+	724	256
17	Reserved	—	724	343
18	Reserved	—	724	418
19	17	P0.7/IREF0	724	506
20	18	P0.6/CNVSTR	724	606
21	Reserved	—	618	785
22	19	P0.5/RX	–17	785
23	20	P0.4/TX	–117	785
24	21	P0.3/XTAL2	–217	785
25	22	P0.2/XTAL1	–445	785
26	23	P0.1/AGND	–545	785
<b>*Note:</b> Pins marked “Reserved” should not be connected.				

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**Table 3.2. Wafer and Die Information**

<b>Wafer ID</b>	C8051F990B
<b>Wafer Dimensions</b>	8 in
<b>Die Dimensions</b>	1.65 mm x 1.78 mm
<b>Wafer Thickness</b>	12 mil $\pm$ 1 mil
<b>Wafer Identification</b>	Notch
<b>Scribe Line Width</b>	80 $\mu$ m
<b>Die Per Wafer*</b>	Contact Sales for info
<b>Passivation</b>	Standard
<b>Wafer Packaging Detail</b>	Wafer Jar
<b>Bond Pad Dimensions</b>	60 $\mu$ m x 60 $\mu$ m
<b>Maximum Processing Temperature</b>	250 °C
<b>Electronic Die Map Format</b>	.txt
<b>Bond Pad Pitch Minimum</b>	75 mil
<b>*Note:</b> This is the Expected Known Good Die yielded per wafer and represents the batch order quantity (one wafer).	



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## 4. Wafer Storage Guidelines

It is necessary to conform to appropriate wafer storage practices to avoid product degradation or contamination.

- Wafers may be stored for up to 18 months in the original packaging supplied by Silicon Labs.
- Wafers must be stored at a temperature of 18–24 °C.
- Wafers must be stored in a humidity-controlled environment with a relative humidity of <30%.
- Wafers should be stored in a clean, dry, inert atmosphere (e.g. nitrogen or clean, dry air).

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## DOCUMENT CHANGE LIST

### Revision 1.0 to Revision 1.1

- Changed Wafer Packaging Detail to “Wafer Jar” in Table 3.2 on page 8.

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**NOTES:**

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